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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Applicant: Marc Viala et al

Title: "PROCESS FOR MEASURING A THREE-DIMENSIONAL
OBJECT OR A SET OF OBJECTS" Technology Center 2600

Serial No.: 10/019,871

Filing Date: December 26, 2001

Docket: 34191

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INFORMATION DISCLOSURE STATEMENT

Box PCT
Commissioner for Patents
Washington, D.C. 20231

Sir:

The examination of the PCT International Application No. PCT/FR01/01274 corresponding with the above-identified case disclosed the publications listed in the enclosed copy of Patent Office Form 1449. A copy of the publications are enclosed herewith together with a copy of the International Search Report.

It is requested that the publications noted herein be considered by the examiner and made of record in the examination of this application.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Box PCT Commissioner for Patents, Washington, D.C. 20231 on the date indicated below.

Michael W. Garvey
Name of Attorney for Applicant(s)

02-01-2002

Date Signature of Attorney

If there are any fees resulting from this communication, please charge the same to our
Deposit Account No. 16-0820, our Order No. 34191.

Respectfully submitted,

PEARNE & GORDON LLP

B 

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February 1, 2002

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 34191	SERIAL NO. 10/019,871
INFORMATION DISCLOSURE CITATION BY APPLICANT		APPLICANT: Marc Viala et al.	
		FILING DATE: 12/26/2001	GROUP ART UNIT:

U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Name	Class	Subclass	Filing Date If Appropriate
	A	5,537,494	7/1996	Toh			02/1995
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						

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Technology Center 2600

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subclass	Translation
	L	2 272 515 A	5/1994	GB			Cited on ISR
	M	43 25 269 A	2/1995	DE			Cited on ISR
	N						
	Q						

OTHER REFERENCES (including Author, Title, Date, Patent Page, Etc.)

	R	
	S	
	T	

Examiner:	Date Considered
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*Examiner: Initial if reference considered, regardless of whether citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.